Notification Regarding APO

This notice serves as a reminder to parties subject to administrative protective order (APO) of their responsibility concerning the disposition of proprietary information disclosed under APO in accordance with 19 CFR 351.305(a)(3). Timely written notification of the return or destruction of APO materials or conversion to judicial protective order is hereby requested. Failure to comply with the regulations and terms of an APO is a sanctionable violation.

We are issuing and publishing these rescissions in part in accordance with section 777(i)(1) of the Tariff Act of 1930, as amended, and 19 CFR 351.213(d)(4).

Dated: March 19, 2009.

John M. Andersen,

Acting Deputy Assistant Secretary for Antidumping and Countervailing Duty Operations.

[FR Doc. E9–6800 Filed 3–25–09; 8:45 am]

DEPARTMENT OF COMMERCE

International Trade Administration

University of Colorado, et al.; Notice of Consolidated Decision on Applications for Duty–Free Entry of Electron Microscopes

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, as amended by Pub. L. 106–36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Room 3705, U.S. Department of Commerce, 14th and Constitution Avenue., NW, Washington, D.C.

Docket Number: 08–041. Applicant: University of Colorado, Denver, CO 80217. Instrument: Vitrification Robot. Manufacturer: FEI Company, The Netherlands. Intended Use: See notice at 74 FR 7394, February 17, 2009.

Docket Number: 08–052. Applicant: University of Washington, Seattle, WA 98105–6698. Instrument: CTD Chain III. Manufacturer: ADM Electronik, Germany. Intended Use: See notice at 74 FR 7395, February 17, 2009.

Docket Number: 08–056. Applicant: Argonne National Laboratory, Lemont, IL 60439. Instrument: Isobar Separator System. Manufacturer: Bruker Biospin S.A., France. Intended Use: See notice at 74 FR 7395, February 17, 2009.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered. Reasons: Each foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.

Dated: March 19, 2009.

Chris Cassel,

Acting Director, Subsidies Enforcement Office, Import Administration. [FR Doc. E9–6799 Filed 3–25–09; 8:45 am] BILLING CODE 3510–DS–S

DEPARTMENT OF COMMERCE

International Trade Administration

University of Colorado, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscopes

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, as amended by Pub. L. 106–36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 3705, U.S. Department of Commerce, 14th and Constitution Avenue, NW., Washington, DC.

Docket Number: 08–050. Applicant: University of Colorado, Boulder, CO 80309–0427. Instrument: Dual Beam FIB Electron Microscope. Manufacturer: FEI Company, Czech Republic. Intended Use: See notice at 74 FR 7588, February 18, 2009.

Docket Number: 08–051. Applicant: Lawrence Berkeley National Laboratory. Instrument: Electron Microscope. Manufacturer: FEI Company, The Netherlands. Intended Use: See notice at 74 FR 7588, February 18, 2009.

Docket Number: 08–062. Applicant: Carnegie Mellon University, Pittsburgh, PA 15213. Instrument: Scanning Electron Microscope. Manufacturer: FEI Company, The Netherlands. Intended Use: See notice at 74 FR 7588, February 18, 2009.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were

ordered. *Reasons:* Each foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.

Dated: March 19, 2009.

Chris Cassel,

Acting Director, Subsidies Enforcement Office, Import Administration.

[FR Doc. E9-6798 Filed 3-25-09; 8:45 am]

BILLING CODE 3510-DS-P

DEPARTMENT OF COMMERCE

National Oceanic and Atmospheric Administration

RIN 0648-XO24

Endangered and Threatened Species; Take of Anadromous Fish

AGENCY: National Marine Fisheries Service (NMFS), National Oceanic and Atmospheric Administration (NOAA), Commerce.

ACTION: Notice of receipt of a permit application; request for comments.

SUMMARY: Notice is hereby given that NMFS has received an application for a permit (permit 14579) to conduct steelhead rescue activities for population enhancement purposes from the Protected Resource Division of NMFS office in Long Beach (PRDLB), California. The requested permit would affect the Southern California Coast Distinct Population Segment of endangered steelhead trout (Oncorhynchus mykiss). The public is hereby notified of the availability of the permit application for review and comment before NMFS either approves or disapproves the application.

DATES: Written comments on the permit application must be received at the appropriate address or fax number (see **ADDRESSES**) on or before April 27, 2009.

ADDRESSES: Written comments on the permit application should be sent to Matt McGoogan, Protected Resources Division, NMFS, 501 W. Ocean Blvd., Suite 4200, Long Beach, CA 90802. Comments may also be sent using email (FRNpermits.lb@noaa.gov) or fax (562) 980–4027. The permit application is available for review, by appointment, at the foregoing address and is also available for review online at the Authorizations and Permits for